

ABSTRACT

A probe card, and a probe sheet used for the method of testing (producing) a semiconductor device using the probe card, include first contact terminals in electrical contact with the electrodes of a test object formed at a narrow pitch, wires connected with and led from the first contact terminals, and second contact terminals in electrical contact with the wires. The first and second contact terminals are formed using the etching holes of a crystalline member and lined with a metal sheet.